

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/612,448	QIAN ET AL.	
Examiner		Art Unit	Mark A. Chapman	
		1756	Page 1 of 1	

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,204,219	04-1993	Van Ooij et al.	430/272.1
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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